L Number	Hits	Search Text	i DB	Time stamp
1	2799	250/341.8,306,307,559.3.ccls.	USPAT;	2003/10/22 15:11
' 	2,00	200704 1.0,000,007,000.0.0013.	US-PGPUB; EPO; JPO;	2000/10/22 10:11
2	87	"critical dimension" AND 250/341.8,306,307,559.3.ccls.	IBM_TDB USPAT;	2003/10/22 15:12
 		ļ i	US-PGPUB; EPO; JPO;	
3	93	(ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4 nanometrology) AND 250/341.8,306,307,559.3.ccls.	IBM_TDB USPAT; US-PGPUB;	2003/10/22 15:12
			EPO; JPO; IBM_TDB	
] ~ 	0	scatterometry AND 250/237R.ccls.	USPAT; US-PGPUB; EPO; JPO;	2003/08/26 16:35
 - 	205	scatterometry	IBM_TDB USPAT; US-PGPUB;	2003/08/26 16:40
-	963	profilometry	EPO; JPO; IBM_TDB USPAT;	2003/08/26 16:40
			US-PGPUB; EPO; JPO; IBM_TDB	
-	0	250/237R.ccls. AND profilometry	USPAT; US-PGPUB; EPO; JPO;	2003/08/26 16:42
-	8	(scatterometry OR profilometry) AND 356/614,616,620.ccls.	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/09/03 13:27
-	8	(scatterometry OR profilometry OR reflectometry) AND 356/614,616,620.ccls.	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/09/03 14:09
-	4106	(ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4) AND (pitch OR dimension)	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/10/07 11:28
-	1	((ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4) AND (pitch OR dimension)) AND 250/237R.ccls.	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/09/03 14:11
-	331	250/\$.ccls. AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4) AND (pitch OR dimension))	IBM_TDB USPAT; US-PGPUB;	2003/09/03 14:11
	004		EPO; JPO; IBM_TDB	2002/00/02 44:40
-	224	(wafer substrate (integrated ADJ circuit)) AND (250/\$.ccls. AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4) AND (pitch OR dimension)))	USPAT; US-PGPUB; EPO; JPO; IBM TDB	2003/09/03 14:12
-	142	((wafer substrate (integrated ADJ circuit)) AND (250/\$.ccls. AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4) AND (pitch OR dimension)))) AND	USPAT; US-PGPUB; EPO; JPO;	2003/09/03 15:33
-	714	@pd<20020225 ((determin\$5 measur\$4) NEAR4 (period pitch dimension)) AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4) AND (pitch OR dimension))	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/09/03 15:32
-	219	356/\$.ccls. AND (((determin\$5 measur\$4) NEAR4 (period pitch dimension)) AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4) AND (pitch OR dimension)))	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/09/03 15:33
Search Histor		3 3:17:29 PM Page 1	IBM_TDB	

Search History 10/22/03 3:17:29 PM Page 1

-	131	(356/\$.ccls. AND (((determin\$5 measur\$4) NEAR4 (period	USPAT;	2003/09/03 15:33
		pitch dimension)) AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4) AND (pitch OR dimension))))	US-PGPUB; EPO; JPO;	
		AND @pd<20020225	IBM_TDB	
-	672	356/614,616,620.ccls.	USPAT;	2003/10/07 11:28
	1		US-PGPUB;	
			EPO; JPO;	
			IBM_TDB	
ļ -	1144	250/237R.ccls.	USPAT;	2003/10/07 11:28
			US-PGPUB;	
			EPO; JPO;	
	:		IBM_TDB	
-	1	("6433878").PN.	USPAT;	2003/10/07 14:23
	1		US-PGPUB;	
			EPO; JPO;	
			IBM_TDB	
-	9	("4870289" "5164790" "5413884" "5576829" "5879844"	USPAT	2003/10/07 14:23
		"5962173" "5963329" "6137570" "6187483").PN.		
l -	17	(ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4	USPAT;	2003/10/22 15:12
		nanometrology) AND (356/614,616,620.ccls. 250/237R.ccls.)	US-PGPUB;	
i l			EPO; JPO;	
•			IBM_TDB	
-	8	((feature OR structure) WITH (dimension OR measurement	USPAT;	2003/10/09 17:15
		OR pitch)) AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4	US-PGPUB;	
		scatteromet\$4 nanometrology) AND (356/614,616,620.ccls.	EPO; JPO;	
		250/237R.ccls.))	IBM_TDB	
-	1	("6433878").PN.	USPAT;	2003/10/14 15:02
	!		US-PGPUB;	
i	i		EPO; JPO;	! !
	į		IBM_TDB	: :
-	1735	(356/399,495,503,625,634,635,630,640).CCLS.	USPAT;	2003/10/20 17:39
			US-PGPUB;	; i
			EPO; JPO;	
			IBM_TDB	
-	161	(ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4	USPAT;	2003/10/20 17:40
		nanometrology) AND	US-PGPUB;	
		((356/399,495,503,625,634,635,630,640).CCLS.)	EPO; JPO;	
			IBM_TDB	
-	9	("5867276" "5877880" "5880838" "6051348" "6081334"	USPAT	2003/10/21 13:00
Ī		"6141107" "6245584" "6383888" "6423977").PN.		
-	11107	"integrated circuit" AND pitch AND pattern	USPAT;	2003/10/21 15:13
			US-PGPUB;	
			EPO; JPO;	!
			IBM_TDB	
-	43	scatterometry AND ("integrated circuit" AND pitch AND	USPAT;	2003/10/22 15:10
		pattern)	US-PGPUB;	
			EPO; JPO;	
			IBM_TDB	